



# Deviation from Bragg scattering



Transmission Electron Microscopy

Welcome to CIME's lectures on transmission electron microscopy for materials science. In the last lecture, we saw how the size and shape of the sample, in particular the fact that it is very thin, leads to the reciprocal lattice nodes having an elongated form; the so-called reciprocal lattice rod or relrod form. And it is this elongation that gives the relaxation of the Bragg condition, which in turn allows us to start understanding why, in a zone axis condition, we have such strong scattering from many different crystal planes at the same time. In this lecture, we are going to consider in more detail the intensity along one of these reciprocal lattice rods; but looking not at the zone axis condition, but instead at the two-beam electron diffraction condition. And further, considering what happens to the intensity in a diffracted beam when we deviate slightly from this perfect Bragg scattering condition.

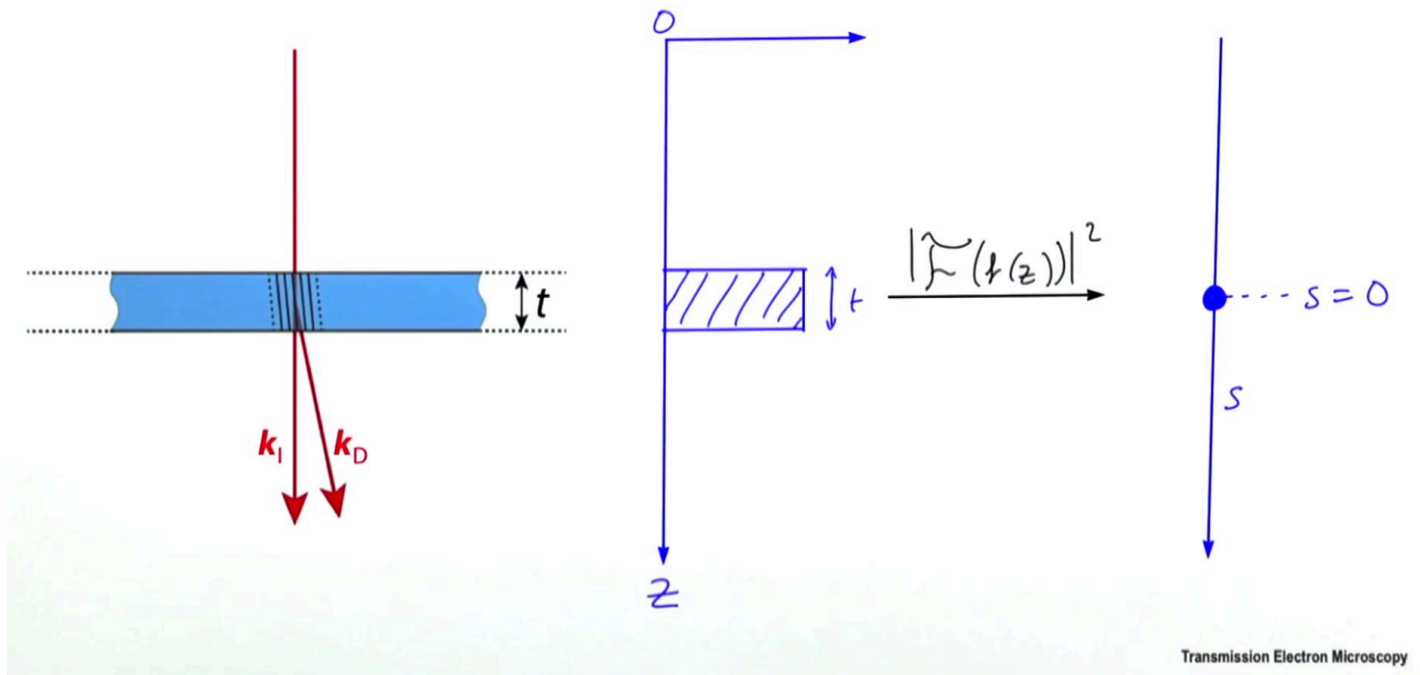
Notes

Summary



0m 05s

# Fourier transform of sample thickness



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Here, we have a schematic diagram of our sample with strong scattering from this Bragg plane into this diffracted beam  $k_D$ , and the sample having a thickness of  $t$ . To calculate the intensity along our relrod, we need to determine the Fourier transform of this sample thickness. Effectively, the sample is like a top hat function along this  $z$ -axis. We have a function which is either at maximum within the sample, or along the rest of  $z$  has a value of zero. We need to calculate the Fourier transform of this function. Once we have identified that, by taking its modulus, squared, we can obtain the intensity distribution along this axis. This, we will plot in reciprocal space along the axis of the relrod. And for reasons that will become clear, we will call the distance along this relrod " $s$ ", with a center of the relrod corresponding to  $s$  equals zero.

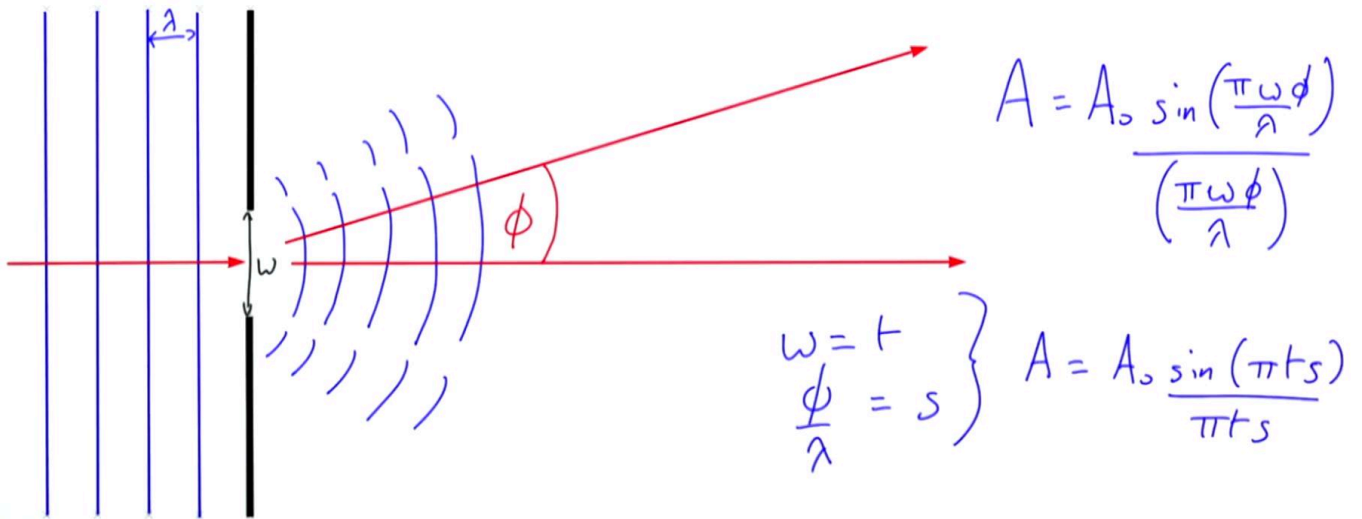
Notes

Summary



1m 04s

# Single slit scattering analogy



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The amplitude and intensity distributions of that top hat function are equivalent to those from the scattering of a plane wave by a single slit with width  $w$ . Here, we look at such a plane wave, with a wavelength of  $\lambda$ , incident on the slit which has this width  $w$ . When the wave scatters from that slit, we will obtain some interference pattern, with the waves spreading out, with a central maximum and then other narrower maxima. Looking at the far field, the amplitude of scattering for a scattering angle of  $\phi$  is given by the formula:  $A = A_0 \sin\left(\frac{\pi w \phi}{\lambda}\right) / \left(\frac{\pi w \phi}{\lambda}\right)$ . In other words, we have a sinc function of  $\sin x / x$  multiplied by  $A_0$ , where  $A_0$  is the maximum amplitude observed at scattering angle  $\phi = 0$ . To translate this formula to the TEM case, we know that  $w$  – the width of our slit – is equivalent to the sample thickness  $t$ . And further, it can be easily shown that, in reciprocal space,  $\phi / \lambda$  equals  $s$ ; the distance along our reciprocal lattice rod. Taking these together, we see that:  $A = A_0 \sin(\pi t s) / \pi t s$ .

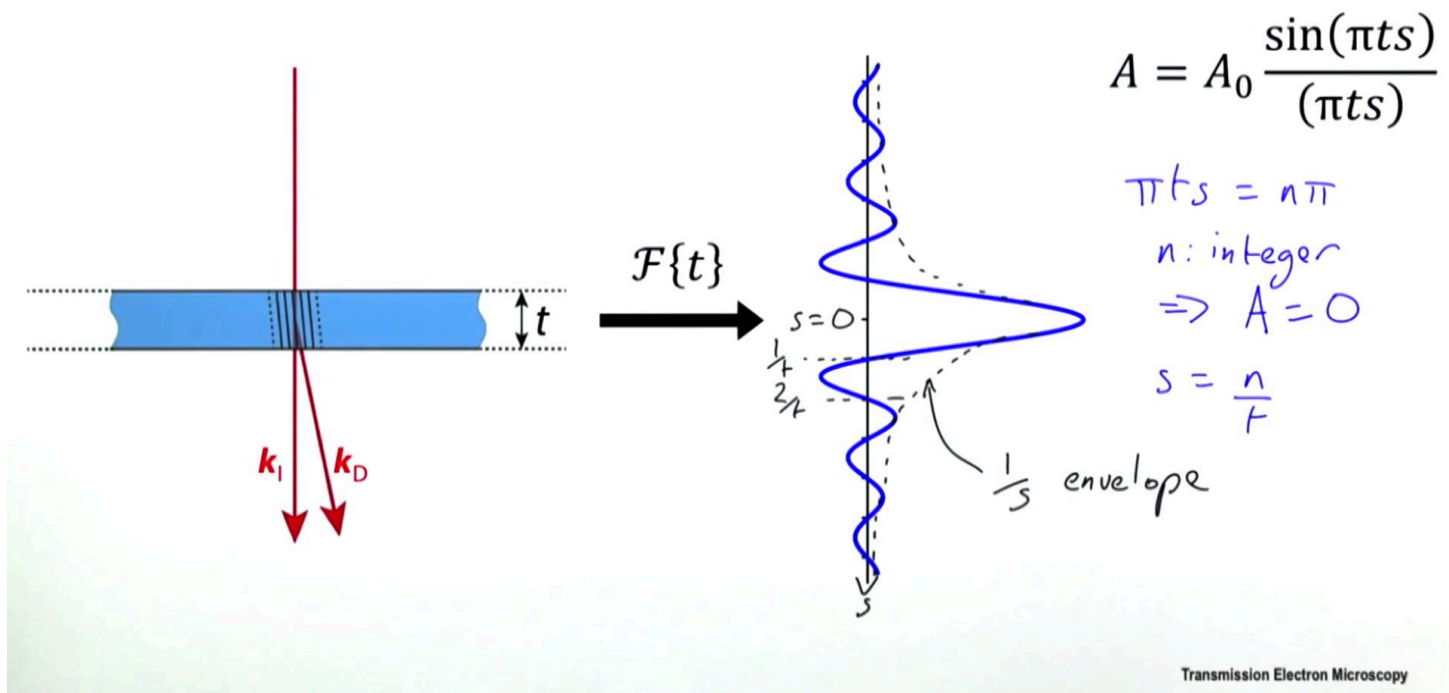
Notes

Summary



2m 17s

# Fourier transform of sample thickness



Plotting out this amplitude function along the length of our reciprocal lattice rod,  $s$ , we obtain an amplitude distribution that looks like this. With these modulations which are strong in the center, where  $s$  equals zero, and decay out either side. Further, considering  $s$  away from zero, it is clear that when:  $\pi t s = n \pi$ , where  $n$  is an integer, that  $A = 0$ . Therefore, we see that for:  $s = n$  divided by  $t$ , we have zeros along this modulation. The first at one divided by thickness; the second at two divided by thickness  $t$ ; and so on. Additionally, we see that these sine type modulations sit within a one over  $s$  envelope. This is the amplitude function, but in diffraction, we measure intensity. To calculate the intensity distribution, we simply need to take the square of this function – corresponding to this Fourier transform multiplied by its complex conjugate.

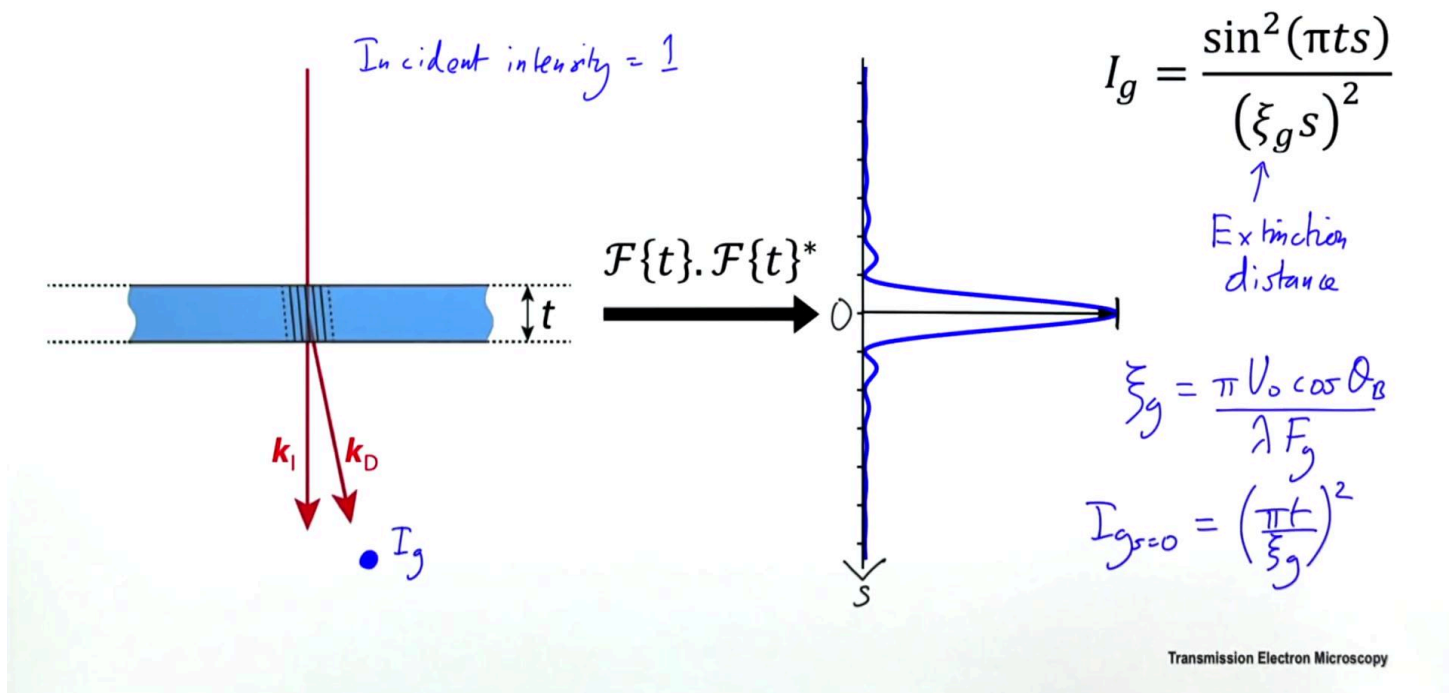
Notes

Summary



3m 57s

# Fourier transform of sample thickness



Looking at this intensity function, we now have an intensity proportional to: sine squared of  $\pi t s$  divided by  $\pi t s$  squared, or sinc squared  $\pi t s$ . Along the  $s$ -axis, we again have a central maximum at  $s$  equals zero. And again, we have zeros in the modulation at  $s = 1$  over  $t$ ,  $2$  over  $t$ , and so on. However, this time, these modulations sit within a  $1$  over  $s$  squared envelope. Here, we make that intensity expression yet more specific to the TEM case, by considering that we have an incident intensity on the sample, equal to one. And now, calculating directly the intensity in a diffracted beam,  $I_g$ . Where  $I_g$  is, again, given by the sine squared of  $\pi t s$  on the top. However, on the bottom, we have a new term. This  $\xi_g$  is known as the extinction distance. And while not proved here it is given by the expression  $\xi_g = \pi$  times the volume of the unit cell times cosine  $\theta_B$ , where  $\theta_B$  is the Bragg angle, divided by  $\lambda$ , the wavelength, times  $F_g$ , where  $F_g$  is the structure factor for that particular reflection. Further, it can be straightforwardly shown that the intensity at the tip of the central maximum – at  $s$  equals zero – is given by the expression  $I_{g,s=0} = \pi^2 t^2 / \xi_g^2$ .

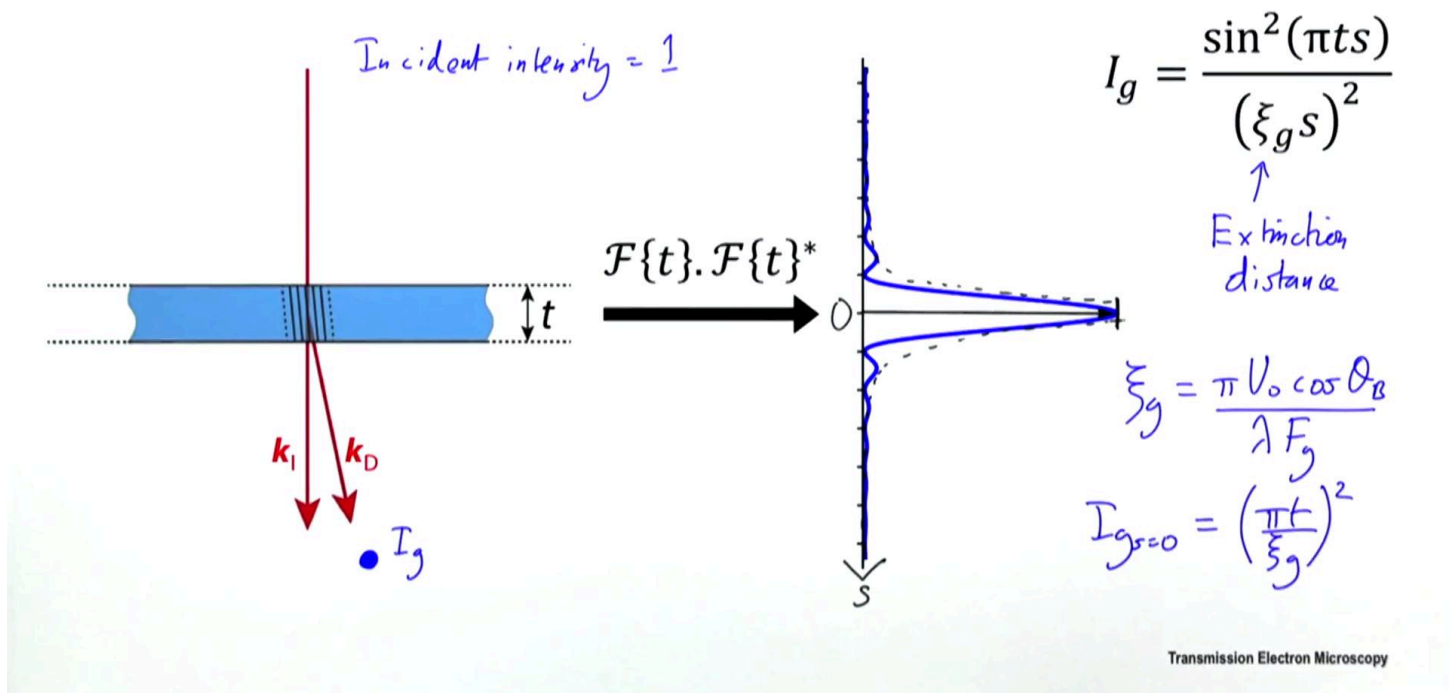
Notes

Summary



5m 14s

# Fourier transform of sample thickness



One thing that is very important to mention at this point is that these expressions only apply in the case of what we call “kinematical scattering”. Kinematical scattering means single elastic scattering. In other words, the beam will be diffracted at most one time on its transmission or trajectory through the sample. While such kinematical scattering is not an accurate assumption during real electron diffraction, where the probability of scattering is very high, nevertheless, this expression, and this intensity distribution, with this one over s squared envelope, will still give useful insights in the remaining slides, where we will interact this relrod intensity distribution with the Ewald sphere.

Notes

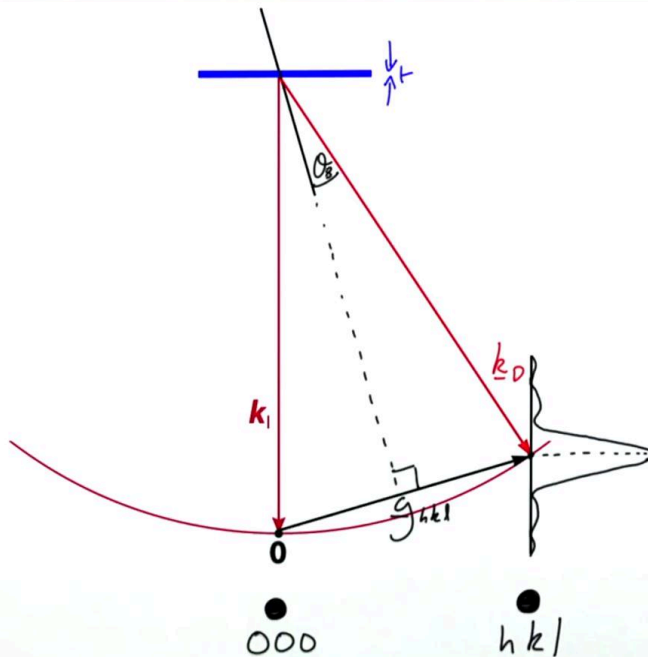
Summary



7m 02s



# Bragg scattering condition



- Ewald sphere intersects reciprocal lattice rod at intensity peak
- Strong scattering into Bragg reflection  $g$  (kinematical approximation)

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On this slide, we are going to make this interaction, looking at the perfect Bragg scattering condition. So we imagine we have a sample of thickness  $t$ , with a plane scattering at a perfect Bragg angle  $\theta_B$ , giving a diffracted beam as follows. Given that we are at the perfect Bragg condition, the center of the reciprocal lattice node is intersected exactly by the Ewald sphere. Thus, we will have a diffraction vector,  $g$ , coming here which is of course perpendicular to our Bragg scattering plane. We know that this reciprocal lattice node is at the center of some reciprocal lattice rod. And now, we are going to plot the intensity distribution along this reciprocal lattice rod. As we saw before, it will have some modulations with a central intense peak. Given that the Ewald sphere intersects in the center of this peak, the diffracted beam will have a strong intensity, given by that maximum. Thus, if we took a diffraction pattern, we will have one bright spot for the  $0\ 0\ 0$  – the direct beam – and another very bright spot for the diffracted beam  $h\ k\ l$ . On the next slide, we will look at what happens to the intensity in this diffracted beam when we now tilt this diffracting plane slightly away from that perfect Bragg condition.

Notes

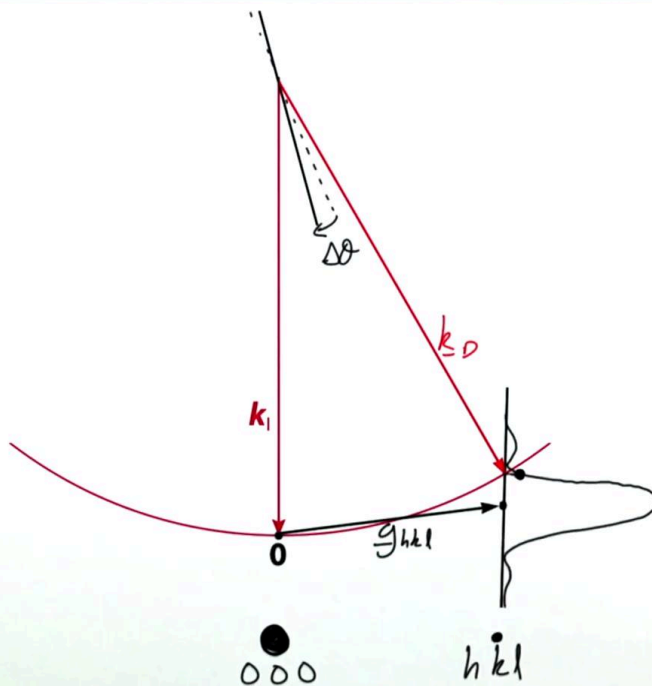
Summary



7m 47s



# Tilted slightly off Bragg condition



- Tilt plane by  $\Delta\theta$
- Introduce vector  $\mathbf{s}_g$  parallel to  $\mathbf{k}_I$  to describe deviation from Bragg condition

$$\underline{k}_D = \underline{k}_I + \mathbf{g}$$

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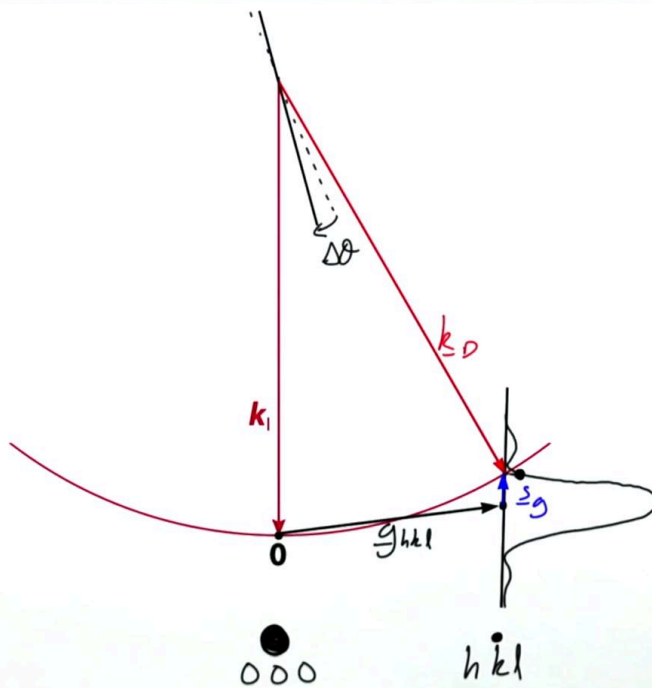
On this slide, if that diffracting plane was previously at this angle, it has now been tilted slightly by an angle  $\Delta\theta$  towards the incident electron beam. Since the reciprocal lattice vector is perpendicular to this plane, it also is rotated by an angle,  $\Delta\theta$ , compared to previously. The reciprocal lattice rod is going to be centered on this vector,  $\mathbf{g}$ , as follows. With the Ewald sphere intersecting this rod here, the diffraction vector  $\mathbf{k}_D$  plots as follows. Sketching in the intensity modulations along the reciprocal lattice rod, we see that, unlike the perfect Bragg condition, where the intensity in the diffracted beam was given by the maximum in this central peak, the intensity in that diffracted beam is now given by this locus here. Thus, clearly, if we now sketch a diffraction pattern, while the direct beam will be strong, the intensity in that diffracted beam will be much smaller than before. Thus, this deviation away from the perfect Bragg condition has led to a dramatic weakening of intensity in the diffracted beam. In addition, the vectorial expression we had before for perfect Bragg diffraction, where  $\mathbf{k}_D$  equals  $\mathbf{k}_I$ , the incident wave vector, plus  $\mathbf{g}$ , the diffraction vector, no longer applies.

Notes

Summary



# Tilted slightly off Bragg condition



- Tilt plane by  $\Delta\theta$
- Introduce vector  $\underline{s}_g$  parallel to  $\underline{k}_I$  to describe deviation from Bragg condition

$$\underline{k}_D = \underline{k}_I + \underline{g} + \underline{s}_g$$

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To solve this, we now introduce another vector, which we will call  $\underline{s}_g$ . By closing the loop, we obtain:  $\underline{k}_D = \underline{k}_I + \underline{g} + \underline{s}_g$ , where essentially,  $\underline{s}_g$  describes the deviation from the perfect Bragg condition.

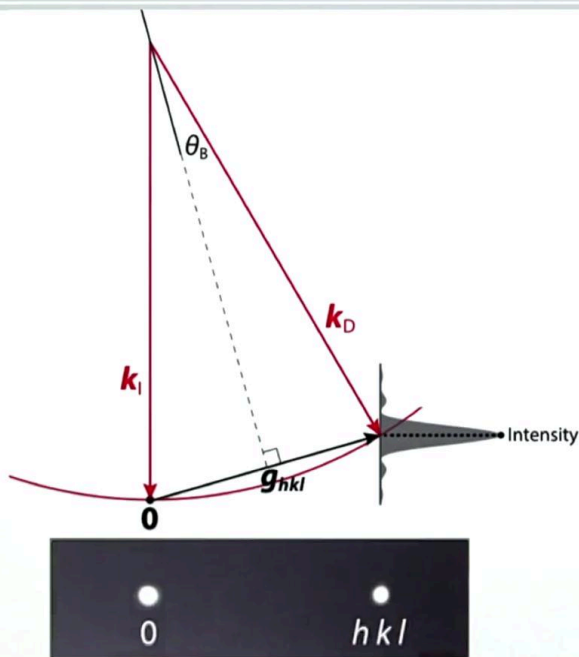
Notes

Summary



10m 49s

# The excitation/deviation vector



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Cleaning these two diagrams up, here we have the schematic illustration for scattering at the perfect Bragg condition, where the Ewald sphere intersects the center of the relrod. Thus, giving an intensity in the diffracted beam which corresponds to the maximum in this sinc squared function, as demonstrated by this real experimental diffraction pattern here.

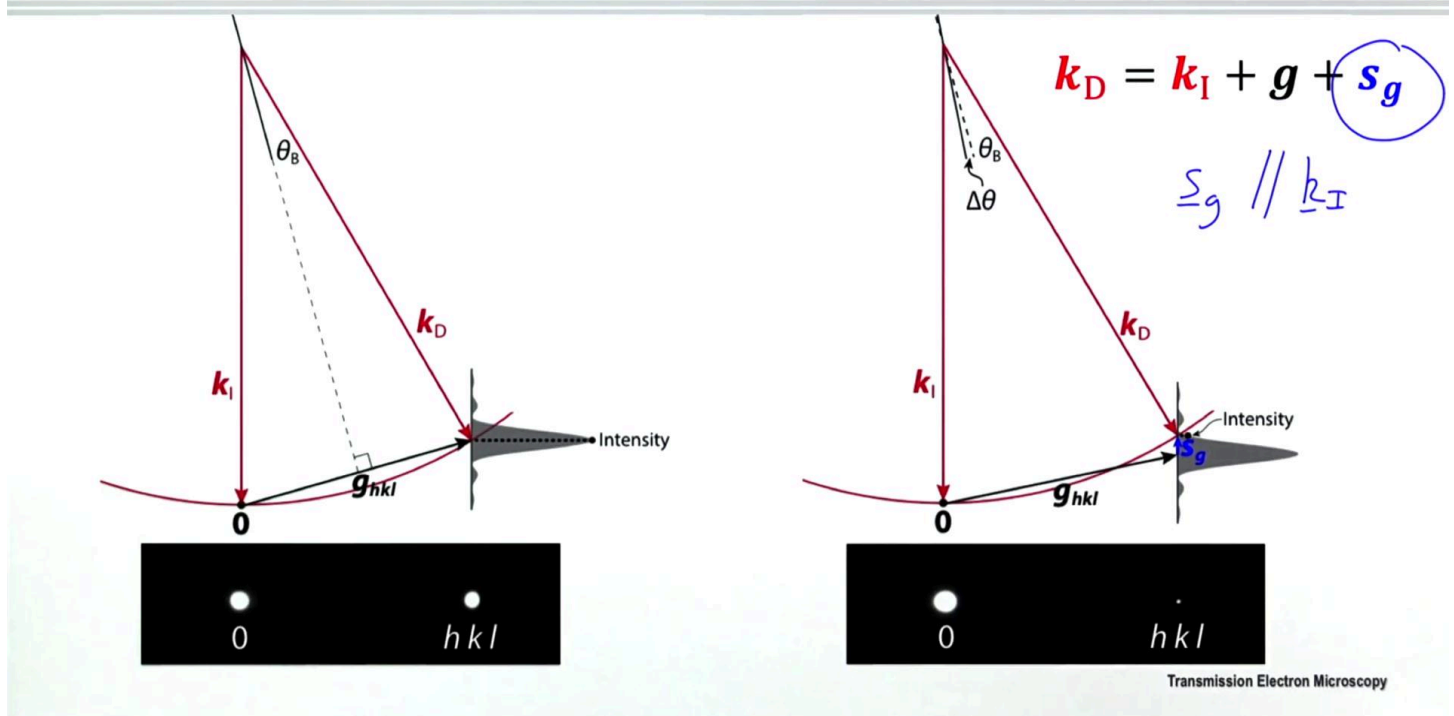
Notes

Summary



11m 11s

# The excitation/deviation vector



Now tilting away from that perfect Bragg condition by a small amount  $\Delta\theta$ , the Ewald sphere intersects away from the center of that peak, resulting in a significant decrease in the intensity of that diffracted beam. Given the one over  $s$  squared envelope for this intensity distribution, for a sample with a typical thickness of 50 or 100 nanometers,  $\Delta\theta$  just needs to be a fraction of a degree for us to observe a significant reduction in the intensity of this diffracted beam. Finally, to describe this deviation away from the perfect Bragg condition, we introduce this new vector  $s_g$ . Where in this case, I define  $s_g$  as being parallel to the incident wave vector  $k_I$ . Further,  $s_g$  is known under two expressions: either the excitation or deviation vector.

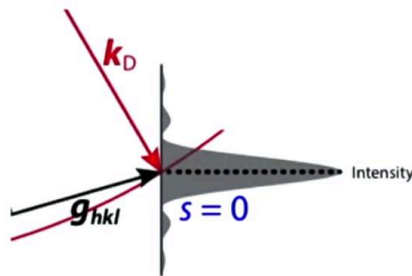
Notes

Summary

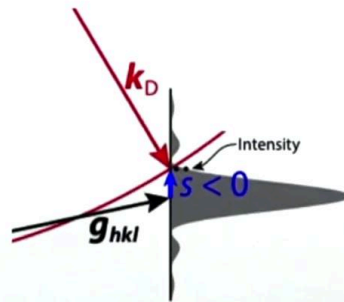
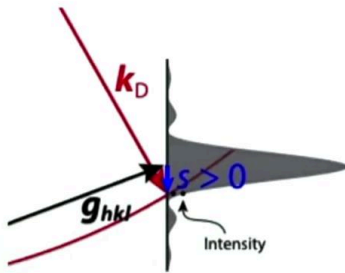


11m 36s

# Excitation error/deviation parameter



- $s$ : scalar quantity of  $s_g$
- Known as “excitation error” or “deviation parameter” ( $s \xi_g$ )
- Specified in  $\text{nm}^{-1}$



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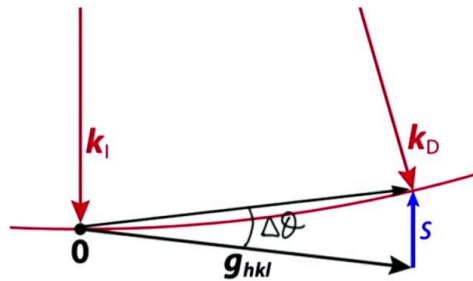
Having defined  $s_g$ , I now introduce a scalar quantity:  $s$ . So  $s$  equals the scalar quantity of  $s_g$ . This  $s$  is again known under two different expressions. One of them being the excitation error; in other words, how much we are in error of exciting a perfect Bragg condition. Or, alternatively, as the deviation parameter; in other words, how far we are in deviation of the perfect Bragg condition. However, it should be known that, while some people refer to  $s$  as being the deviation parameter, in other works, the deviation parameter can refer to a quantity of  $s$  times  $\xi_g$ , the extinction distance. Being in reciprocal space, this excitation error,  $s$ , is typically measured or specified in inverse nanometers. Obviously, for the perfect Bragg condition,  $s = 0$ . Away from the Bragg condition, if  $s$  is within the Ewald sphere, that is corresponding to a tilt of the diffracting plane this way, then  $s$  is greater than 0. And if  $s$  is outside the Ewald sphere, then it is negative; this time instead corresponding to a tilt of the diffracting plane this way relative to the perfect Bragg condition.

Notes

Summary



# Excitation error/deviation parameter

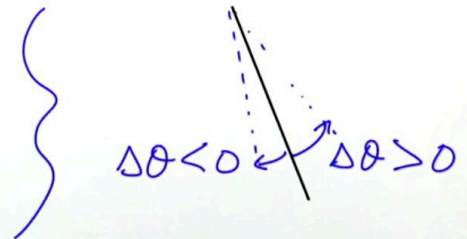


- $s$ : scalar quantity of  $s_g$
- Known as “excitation error” or “deviation parameter”
- Specified in  $\text{nm}^{-1}$

- $s = \frac{\Delta\theta}{d_{hkl}}$

$$\Delta\theta = \frac{s}{|g_{hkl}|}$$

$$|g_{hkl}| = \frac{1}{d_{hkl}}$$



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Looking a bit more at that  $s$  equals negative scenario, here I have a rather symmetrical illustration, where this would be the  $g$  vector for the perfect Bragg condition. Given that the diffracting plane has been tilted away from the perfect Bragg condition by an angle  $\Delta\theta$  – which gives an equivalent tilt angle of this reciprocal lattice vector  $g_{hkl}$  – it is clear from this that, in the small angle of approximation:  $\Delta\theta = s$  divided by the modulus of  $g_{hkl}$ . Given that the modulus of  $g_{hkl}$  simply equals one over the plane spacing  $d_{hkl}$ , we can see that the excitation error,  $s$ , is given by  $\Delta\theta$  divided by  $d_{hkl}$ . We know that in this  $s$  equals negative case, the diffracting plane was tilted this way away from the perfect Bragg condition. Therefore, for signs to correspond, in this case,  $\Delta\theta$  must be negative. Alternatively, tilting the other way from the perfect Bragg condition would give a positive  $\Delta\theta$ .

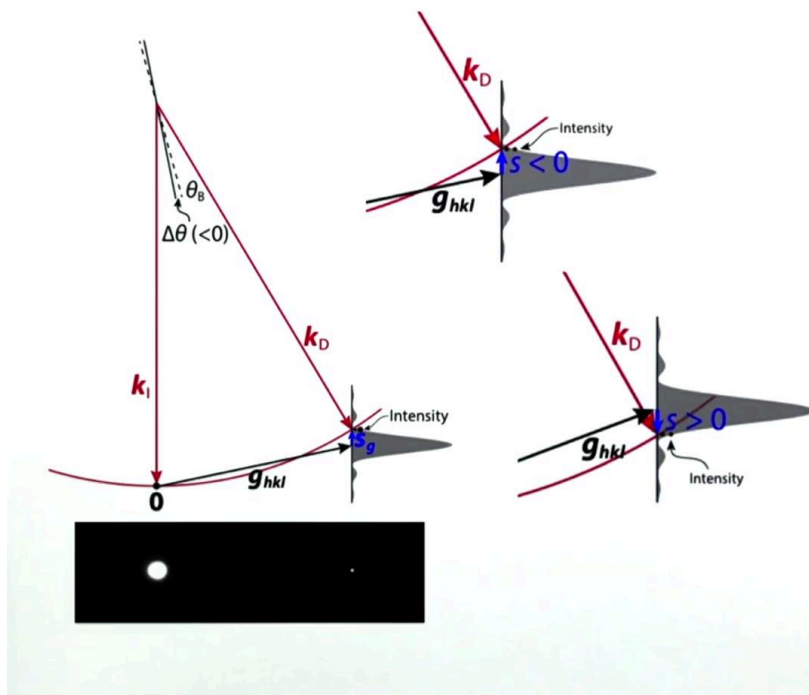
Notes

Summary



13m 53s

# Deviation from Bragg scattering summary



- Intensity modulates along relrod, within  $1/s^2$  envelope
- $s$ : excitation error/ deviation parameter
- $s = 0$ : exact Bragg, intense diffracted beam
- $s > 0$  or  $s < 0$ : weaker intensity in diffracted beam
- Studied kinematical regime (single scattering)

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To summarize, in this lecture, we have seen that the intensity distribution along a reciprocal lattice rod modulates within a one over  $s$  squared envelope, where  $s$  is the excitation error, or deviation parameter. When we are at the exact Bragg condition,  $s$  equals zero, and we will have an intense diffracted beam. However, when  $s$  is away from zero, the intensity in that diffracted beam can decrease dramatically. Further, we define that:  $s$  is greater than zero, when the vector  $s_g$  lies within the Ewald sphere, and it is less than zero, when it is outside the Ewald sphere. While all this may seem a bit abstract, knowledge of the excitation error is critical to certain kinds of diffraction contrast imaging. For instance, for imaging dislocations in weak beam or strong beam conditions. Finally, all this was studied in what is called the kinematical regime, meaning single electron scattering. In reality, in a two-beam condition, we typically have what is called dynamical scattering. This is multiple elastic scattering. In the dynamical case, the modulations along the reciprocal lattice rod will be somewhat different. Indeed, you may not even have a maximum in intensity at  $s$  equals zero, but at  $s$  away from zero.

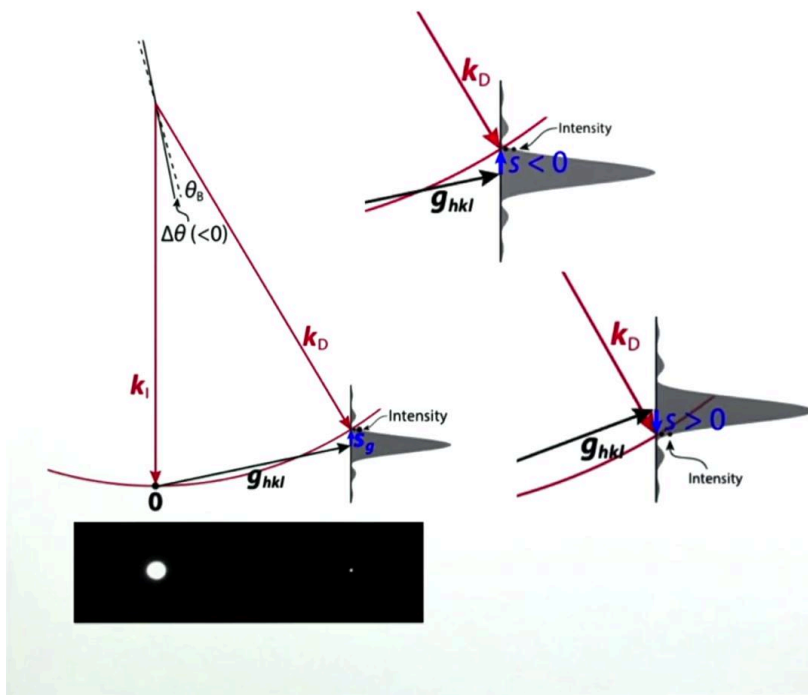
Notes

Summary





# Deviation from Bragg scattering summary



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- $s$ : excitation error/ deviation parameter
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Transmission Electron Microscopy

However, the general principle that the intensity in the diffracted beam is directly related to the intersection of the Ewald sphere with this intensity distribution remains the same. Thus, this kinematical condition provides a useful introduction to a concept needed for understanding dynamical diffraction.

Notes

Summary

